

Snejana M Kitova

List of Publications by Year in descending order

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citing authors

#	ARTICLE	IF	CITATIONS
1	Precious metal-free molecular machines for solar thermal energy storage. Beilstein Journal of Organic Chemistry, 2019, 15, 1096-1106.	2.2	5
2	Ion Beam Induced Surface Modification of ta-C Thin Films. Acta Physica Polonica A, 2017, 132, 299-301.	0.5	0
3	The impact of active layer nanomorphology on the efficiency of organic solar cells based on a squaraine dye electron donor. Journal of Physics: Conference Series, 2016, 700, 012052.	0.4	0
4	Focused ion beam optical patterning of ta-C films. Surface and Coatings Technology, 2016, 306, 341-345.	4.8	2
5	Optical properties of thin merocyanine dye layers for photovoltaic applications. Journal of Physics: Conference Series, 2014, 514, 012019.	0.4	0
6	Optical modeling of bulk-heterojunction organic solar cells based on squaraine dye as electron donor. Journal of Physics: Conference Series, 2014, 558, 012052.	0.4	2
7	Effects of implantation temperature and thermal annealing on the Ga ⁺ ion beam induced optical contrast formation in a-SiC:H. Nuclear Instruments & Methods in Physics Research B, 2013, 307, 71-76.	1.4	3
8	Contact angle analysis of corona treated polypropylene films. Journal of Physics: Conference Series, 2012, 398, 012054.	0.4	18
9	Structural properties of ZnO layers deposited on glass substrates by PECVD. Journal of Physics: Conference Series, 2012, 356, 012024.	0.4	1
10	Effect of the gas composition on the structural and electrical properties of ZnO nanostructures obtained by oxidation of Zn at atmospheric pressure. Journal of Physics: Conference Series, 2012, 398, 012020.	0.4	0
11	Effect of the substrate surface topology and temperature on the structural properties of ZnO layers obtained by plasma enhanced chemical vapour deposition. Journal of Physics: Conference Series, 2010, 223, 012022.	0.4	1
12	Influence of the processing conditions on the structural properties of ZnO layers obtained by PECVD. Journal of Physics: Conference Series, 2010, 253, 012031.	0.4	3
13	Influence of the nickel content on the electrocatalytic activity of thin nanostructured CoTeO films. Journal of Solid State Electrochemistry, 2010, 14, 1073-1078.	2.5	1
14	Deposition of silicon oxynitride films by low energy ion beam assisted nitridation at room temperature. Journal of Physics: Conference Series, 2008, 113, 012028.	0.4	0
15	Reflectance methods for determining the optical constants of highly absorbing films: comparative analysis of the accuracy. Journal of Optics, 2007, 9, 145-151.	1.5	3
16	Electrocatalytic behavior of thin CoTeO films in oxygen evolution and reduction reactions. Electrochimica Acta, 2007, 52, 3794-3803.	5.2	18
17	Thin films of cobalt oxides obtained by a reaction during vacuum deposition. Vacuum, 2004, 76, 147-150.	3.5	3
18	Characterization and photocatalytic activity of Au/TiO ₂ thin films for azo-dye degradation. Journal of Catalysis, 2003, 220, 127-135.	6.2	408

#	ARTICLE	IF	CITATIONS
19	Ion implantation induced surface morphology changes in thin As ₃ Se ₂ films. <i>Vacuum</i> , 2003, 70, 471-475.	3.5	0
20	Surface morphology effects of post-implantation annealing in thin amorphous films of the As-Se system. <i>Vacuum</i> , 2003, 72, 143-147.	3.5	2
21	Optical pattern formation in a-SiC:H films by Ga ⁺ ion implantation. <i>Vacuum</i> , 2002, 69, 73-77.	3.5	17
22	Thin films of cobalt oxides obtained by vacuum co-deposition of Co and TeO ₂ . <i>Vacuum</i> , 2002, 69, 405-409.	3.5	5
23	Vacuum evaporated thin films of mixed cobalt and nickel oxides as electrocatalyst for oxygen evolution and reduction. <i>Electrochimica Acta</i> , 2002, 47, 1555-1560.	5.2	91
24	Photometric methods for determining the optical constants and the thicknesses of thin absorbing films: selection of a combination of photometric quantities on the basis of error analysis. <i>Applied Optics</i> , 2001, 40, 2675.	2.1	14
25	Photometric methods for determining the optical constants and the thicknesses of thin absorbing films: criteria for precise and unambiguous determination of n, k, and d in a wide spectral range. <i>Applied Optics</i> , 2001, 40, 2682.	2.1	16
26	Simulation of the diffraction by CD-R: thickness determination of the dye recording layer. <i>Journal of Optics</i> , 2001, 3, 460-465.	1.5	2
27	Optical properties of phase-change optical disks with Sb _x Se _{100-x} films. <i>Vacuum</i> , 2000, 58, 496-501.	3.5	18
28	Analysis of errors in thin-film optical parameters derived from spectrophotometric measurements at normal light incidence. <i>Applied Optics</i> , 1998, 37, 4260.	2.1	80
29	Sensitivity And Resolution Of Digital Laser Recording Medium Based On Silver Halide Layers. , 1990, , .		0